


<b>Search Notes</b> 	<b>Application/Control No.</b> 10666319	<b>Applicant(s)/Patent Under Reexamination</b> WILSON ET AL.
	<b>Examiner</b> ERIN D CHIEM	<b>Art Unit</b> 2883

SEARCHED			
Class	Subclass	Date	Examiner
385	70-72, 89-94	5/21/08	edc

SEARCH NOTES		
Search Notes	Date	Examiner
wafer same (micro adj lens microlens) and (microlens micro adj lens) same align\$4	12/5/08	edc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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